

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2187	(self test control device or "BIST" or built-in self test or self test circuit) same (integrated circuit or IC)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:27
L2	343	external testing device	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:27
L3	10537	evaluat\$3 same test result\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:28
L4	3	I2 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:28
L5	1	I1 and I4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:28
L6	14	I1 same I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:28
L7	3074	714/733 or 714/734 or 714/30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 08:29
L8	8	I6 and I7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:26

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L9	480146	external test device or external testing device or external test equipment or automatic test equipment or (ATE)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:27
L10	1272	analyz\$3 and (test result\$1) and I9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:27
L11	1	I8 and I10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:36
L12	370	output\$4 and (test result\$1 same (external testing device or ATE or external test equipment))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:37
L13	1	I8 and I12	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:37
L14	8	I8 and I9	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:37
L15	8	I14 and I7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:38
L16	1	I15 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/11/13 09:38